



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Appl. No. 10/090,287 Confirmation No. 6609  
First Inventor Peter G. Borden Filing Date March 1, 2002  
Tech. Center/ 2859 Examiner Verbitsky, Gail  
Art Unit  
Title: Identifying Defects In A Conductive Structure Of A Wafer, Based  
On Heat Transfer Therethrough  
Docket No.: BOX014 US Customer No.: 34036

Santa Clara, California  
December 23, 2003

COMMISSIONER FOR PATENTS  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Dear Sir:

In response to Office Action dated September 25, 2003, please amend the above-identified application as follows.

**Amendments to the Claims** begin on page 2 of this paper.

**Remarks/Arguments** begin on page 10 of this paper.

01/02/2004 ADD01 00000013 10090287

01 FC:1201  
02 FC:1202

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